### **Accepted Manuscript**

Title: Size effect affected mechanical properties and formability in micro plane strain deformation process of pure nickel

Authors: Chuanjie Wang, Haiyang Wang, Shaoxi Xue, Gang Chen, Yibin Wang, Shuting Wang, Peng Zhang

PII: S0924-0136(18)30136-5

DOI: https://doi.org/10.1016/j.jmatprotec.2018.04.001

Reference: PROTEC 15701

To appear in: Journal of Materials Processing Technology

Received date: 13-1-2018 Revised date: 14-3-2018 Accepted date: 1-4-2018

Please cite this article as: Wang C, Wang H, Xue S, Chen G, Wang Y, Wang S, Zhang P, Size effect affected mechanical properties and formability in micro plane strain deformation process of pure nickel, *Journal of Materials Processing Tech.* (2010), https://doi.org/10.1016/j.jmatprotec.2018.04.001

This is a PDF file of an unedited manuscript that has been accepted for publication. As a service to our customers we are providing this early version of the manuscript. The manuscript will undergo copyediting, typesetting, and review of the resulting proof before it is published in its final form. Please note that during the production process errors may be discovered which could affect the content, and all legal disclaimers that apply to the journal pertain.



## ACCEPTED MANUSCRIPT

# Size effect affected mechanical properties and formability in micro plane strain deformation process of pure nickel

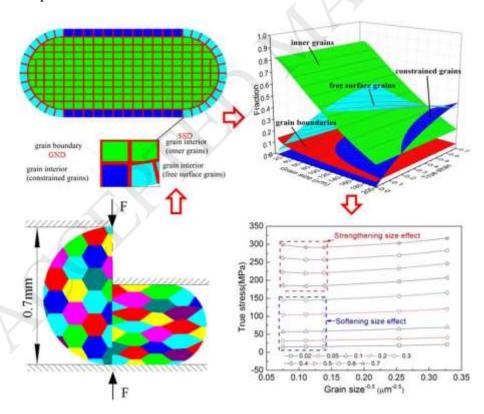
Chuanjie Wang<sup>a</sup>, Haiyang Wang<sup>a</sup>, Shaoxi Xue<sup>a</sup>, Gang Chen<sup>a</sup>, Yibin Wang<sup>a</sup>, Shuting Wang<sup>a</sup>, Peng Zhang<sup>\*a</sup>

<sup>a</sup>School of Materials Science and Engineering, Harbin Institute of Technology at Weihai, Weihai 264209, China

\*Correspondence information: Peng Zhang, E-mail address: pzhang@hit.edu.cn TEL:

+86 631 5687324, FAX: +86 631 5687305

#### **Graphical Abstract**



#### Download English Version:

## https://daneshyari.com/en/article/7176350

Download Persian Version:

https://daneshyari.com/article/7176350

<u>Daneshyari.com</u>